Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/623,569	MIYANO ET AL.	
Examiner	Art Unit	
Anish Desai	1771	

	SEAR	CHED	
Class	Subclass	Date	Examiner
428	354	5/3/2006	APD

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor search using EASt	5/3/2006	APD
Text search using EAST	5/3/2006	APD